

Notice of References Cited	Application/Control No. 10/760,300	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Shantell Heiber	Art Unit 2617	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0044979	03-2004	Aji et al.	716/013
*	B	US-2004/0165561	08-2004	Chiou et al.	370/338
*	C	US-6,535,745	03-2003	Seraj, Jila	455/458
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	K	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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